

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/757,901	OIKAWA ET AL.
	Examiner	Art Unit
	Alain L. Bashore	1762

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
427	127-128	12/4/2006	AB
427	130	12/4/2006	AB
427	132	12/4/2006	AB
428/ 629,632, 668,669		12/4/2006	ab